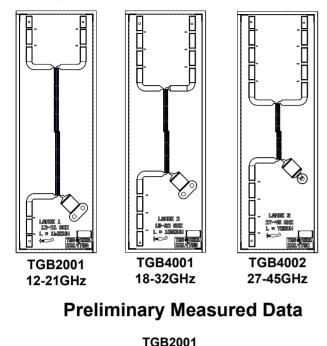


Lange Coupler Set



Product Data Sheet Aug 5, 2008 TGB2001 TGB4001 TGB4002

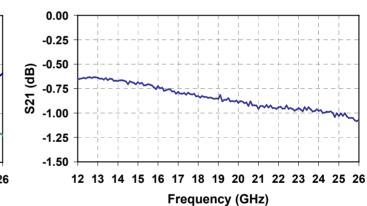
Key Features and Performance

- Very Low Loss (<0.25dB Typical)
- High Power 1W 50Ω Termination
- Broadband 3dB Power Split
- Chip dimensions: 1.0 x 3.0 x 0.1 mm (40 x 120 x 4 mils)
- 3 sizes Cover 12GHz 45GHz

TGB2001 Back-to-Back

Primary Applications

Power Combining



Note: Datasheet is subject to change without notice.



Product Data Sheet

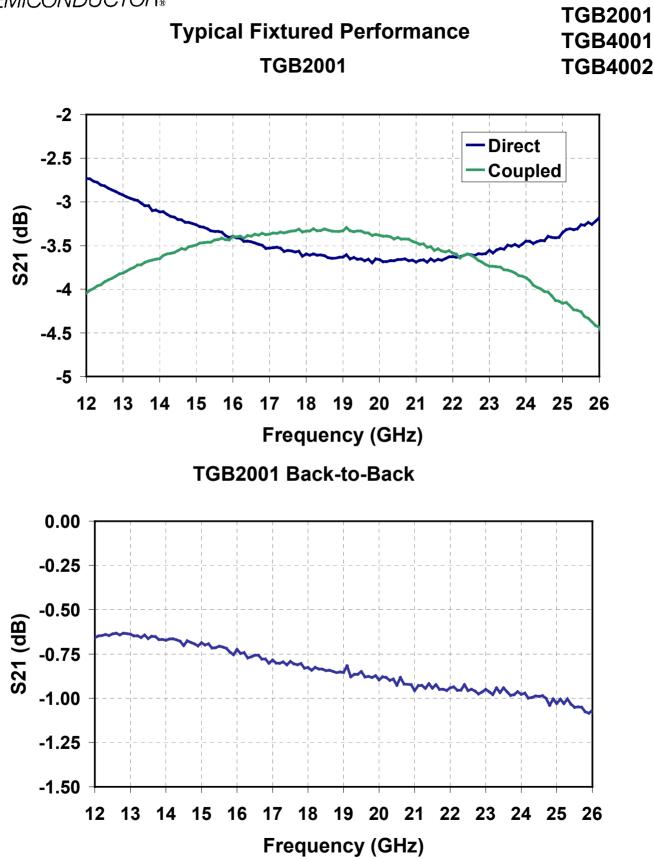
TGB2001 TGB4001 TGB4002

TABLE I MAXIMUM RATINGS

Symbol	Parameter 1/	Value	Notes
P _{IN}	Input Continuous Wave Power	TBD dBm	
T _M	Mounting Temperature	320 ⁰ C	
	(30 Seconds)		
T _{STG}	Storage Temperature	-65 to 150 ⁰ C	

1/ These ratings represent the maximum operable values for this device.





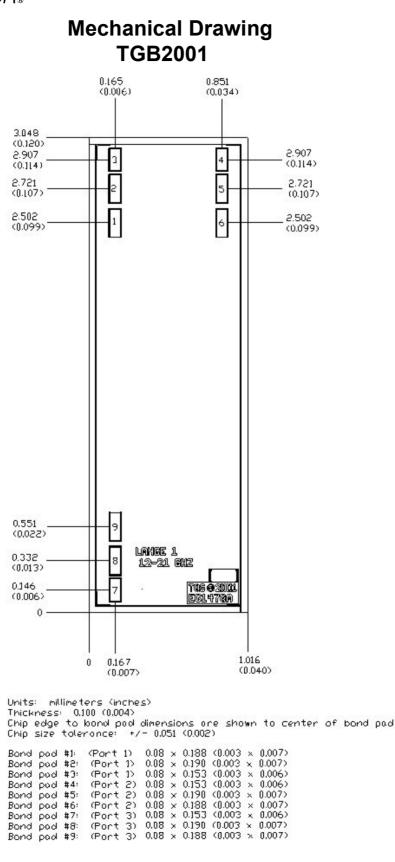
(3

TGB2001

TGB4001

TGB4002





(2.889

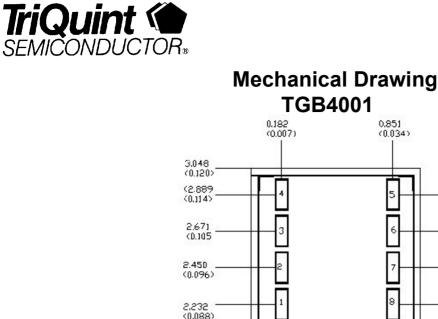
(0.114) 2.671

(0.105

2.450

2.232 (0.088)

(0.096)



(0.088)

0.831

0.612 (0.024)

0.392

(0.015)

0.173 _ <0.007>

0 -

(0.033)

12

10

9

0.184 (0.007)

0

TGB2001 TGB4001 TGB4002

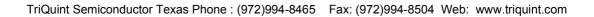
Units: millimeters (inches)	5		
Thickness: 0.100 (0.004)			
Chip edge to band pod di	inensions ore	shown to center o	of bond pod
Chip size tolerance: +/-			
Bond pad #1: (Port 1)	0.09 × 0.189	<0.003 × 0.007)	
Bond pod #2: (Port 1)		(D.003 × 0.007)	
Bond pod #3: (Port 1)		(0.003 × 0.007)	
Bond pad #4: (Port 1)	0.08 × 0.188	<0.003 × 0.007)	
Bond pad #5: (Port 2)	0.08 × 0.189	(0.003 × 0.007)	
	0.08×0.190	(D.003 x 0.007)	
Bond pod #7: (Port 2)	0.08 × 0.190	(0.003 × 0.007)	
Bond pad #8: (Port 2)	0.08 × 0.188	<0.003 × 0.007)	
Bond pad #9: (Port 3)	0.08 × 0.188	(0.DO3 × 0.007)	
Bond pod #10: (Port 3)	0.08 × 0.190	(0.003 × 0.007)	
Bond pod #11: (Port 3)	0.08 × 0.190	(0,003 × 0.007)	
Bond pool #12: (Port 3)	0.08×0.188	(0.003 × 0.007)	

LANGE 2

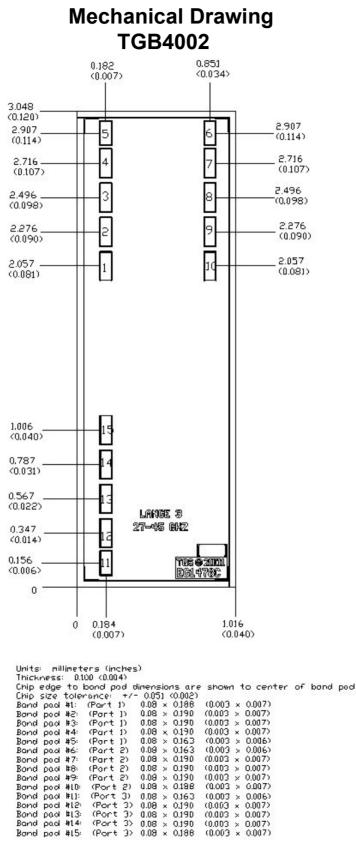
19-32 GHZ

10802000 EG14778B

1.016 (0.04>







TGB2001 TGB4001 TGB4002





TGB2001 TGB4001 TGB4002

Assembly Process Notes

Reflow process assembly notes:

- Use AuSn (80/20) solder with limited exposure to temperatures at or above 300°C. (30 seconds maximum)
- An alloy station or conveyor furnace with reducing atmosphere should be used.
- No fluxes should be utilized.
- Coefficient of thermal expansion matching is critical for long-term reliability.
- Devices must be stored in a dry nitrogen atmosphere.

Component placement and adhesive attachment assembly notes:

- Vacuum pencils and/or vacuum collets are the preferred method of pick up.
- Air bridges must be avoided during placement.
- The force impact is critical during auto placement.
- Organic attachment can be used in low-power applications.
- Curing should be done in a convection oven; proper exhaust is a safety concern.
- Microwave or radiant curing should not be used because of differential heating.
- Coefficient of thermal expansion matching is critical.

Interconnect process assembly notes:

- Thermosonic ball bonding is the preferred interconnect technique.
- Force, time, and ultrasonics are critical parameters.
- Aluminum wire should not be used.
- Discrete FET devices with small pad sizes should be bonded with 0.0007-inch wire.
- Maximum stage temperature is 200°C.

GaAs MMIC devices are susceptible to damage from Electrostatic Discharge. Proper precautions should be observed during handling, assembly and test.